

INFORMATION DISCLOSURE STATEMENT

Pursuant to MPEP § 609, Applicants understand that the Examiner will, as part of his examination of this application, consider the art of record in the parent application (and the grandparent application). A form PTO-1449 is enclosed, citing, inter alia, the art of record in the parent application, but, pursuant to MPEP § 609, no copies of such art are provided; should the Examiner wish to have such submitted, however, Applicants will gladly do so upon request.

English translations and/or English Abstracts of at least some of the listed non-English documents were of record in the parent application, and the Examiner is respectfully referred to those translations/Abstracts with regard to relevance for the corresponding non-English documents.

Applicants also direct the Examiner's attention to the Office Actions (dated March 18, 2003 and September 8, 2003) issued in related Application No. 10/235,811. One copy of each Office Action is attached.

U.S. Patent 6,169,356 issued from U.S. Application No. 08/264,497, of record in the parent application.

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) <i>(Use several sheets if necessary)</i>				ATTY DOCKET NO. 03500.011080.9		APPLICATION NO. NYA	
				APPLICANT YOSHIKAZU BANNO ET AL.			
				FILING DATE FILED HEREWITH			GROUP 1734
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		3,611,077	10/71	Smith	315	94	
		5,023,110	6/91	Nomura et al.	427	49	
		5,650,199	7/97	Chang et al.	427	333	
		5,320,703	6/94	Ikeda	117	68	
		4,566,186	1/86	Bauer et al.	29	852	
		4,668,533	5/87	Miller	427	98	
		4,891,242	1/90	Ito et al.	427	53.1	
		5,114,744	5/92	Cloutier et al.	427	96	
		5,275,646	1/94	Marshall et al.	106	20B	
		5,401,535	3/95	Bishop	427	229	
		5,832,595	11/98	Maruyama et al.	29	829	
		5,861,227	1/99	Ikeda et al.	430	31	
		5,505,777	4/96	Ciardella	118	663	
		5,498,444	3/96	Hayes	427	162	
		4,600,137	7/86	Comerford	228	102	
		5,593,499	1/97	Stans	118	63	
		6,169,356	1/01	Ohnishi et al.	313	495	
		5,569,974	10/96	Morikawa et al.	313	310	
		5,066,883	11/91	Yoshioka et al.	313	309	
EXAMINER				DATE CONSIDERED			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		5,627,111	5/97	Tsukamoto et al.	438	20	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
		0620581A	10/94	EPO			
		0658916A2	6/95	EPO			
		JP0256822	2/90	Japan			
		2-247939	10/90	Japan			
		64-5095	1/89	Japan			
		62-181490	8/87	Japan			
		63-200041	8/88	Japan			
		64-64290	3/89	Japan			
		1-296532	11/89	Japan			
		4-121702	4/92	Japan			
		JP 63-200041	8/88	Japan			
		2,013,233	9/90	Canada			English
		EP 0 394 698	10/90	EPO			
		JP 3-55738	3/91	JAPAN			Abstract
EXAMINER				DATE CONSIDERED			

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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		6,511,545	1/03	Banno et al.	118	688	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
		JP 63-200041	8/88	Japan			
OTHER DOCUMENT(S) <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>							
		Patent Abstracts of Japan, Vol. 014, No. 573 (E-1015), December 19, 1990 & JP 02 247939 A (CANON INC.) October 3, 1990					
		H. Araki et al., "Electroforming and Electron Emission of Carbon Thin Films", J. Vac. Soc. Jpn., 26, 1, 22-29 (1981)					
		M. Hartwell et al., "Strong Electron Emission From Patterned Tin-Indium Oxide Thin Films", Int'l Electron Devices Mtg., Washington, D.C., 519-21 (1975)					
		G. Dittmer, "Electrical Conduction and Electron Emission of Discontinuous Thin Films", Thin Solid Films, 9, 317-28 (1972)					
		W. Dyke et al., "Field Emission", Advances in Electronics and Electron Phys., 89-185 (1956)					
		M. Elinson et al., "The Emission of Hot Electrons and the Field Emission of Electrons from Tin Oxide", Radio Eng'g and Electronic Phys., 1290-96 (1965).					
		C. Mead, "Operation of Tunnel-Emission Devices", J. App. Phys., 32(4), 646-52 (1961).					
		C. Spindt et al., "Physical Properties of Thin-Film Field Emission Cathodes with Molybdenum Cone," J. App. Phys., 47(12), 5240-63 (1976).					
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